

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/606,060	JEPSON ET AL.
	<b>Examiner</b> Michael Pak	<b>Art Unit</b> 1646

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
STIC search SEQ ID NO: search - attached		9/23/2005	MDP